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Understanding [Embedded - Microprocessors](#)

Embedded microprocessors are specialized computing chips designed to perform specific tasks within an embedded system. Unlike general-purpose microprocessors found in personal computers, embedded microprocessors are tailored for dedicated functions within larger systems, offering optimized performance, efficiency, and reliability. These microprocessors are integral to the operation of countless electronic devices, providing the computational power necessary for controlling processes, handling data, and managing communications.

Applications of [Embedded - Microprocessors](#)

Embedded microprocessors are utilized across a broad spectrum of applications, making them indispensable in

Details

Product Status	Obsolete
Core Processor	PowerPC e500
Number of Cores/Bus Width	1 Core, 32-Bit
Speed	1.0GHz
Co-Processors/DSP	Signal Processing; SPE, Security; SEC
RAM Controllers	DDR, DDR2, SDRAM
Graphics Acceleration	No
Display & Interface Controllers	-
Ethernet	10/100/1000Mbps (4)
SATA	-
USB	-
Voltage - I/O	1.8V, 2.5V, 3.3V
Operating Temperature	0°C ~ 105°C (TA)
Security Features	Cryptography, Random Number Generator
Package / Case	783-BBGA, FCBGA
Supplier Device Package	783-FCBGA (29x29)
Purchase URL	https://www.e-xfl.com/pro/item?MUrl=&PartUrl=mpc8548epxaqgb

- Single inbound doorbell message structure
- Facility to accept port-write messages
- PCI Express interface
 - PCI Express 1.0a compatible
 - Supports x8,x4,x2, and x1 link widths
 - Auto-detection of number of connected lanes
 - Selectable operation as root complex or endpoint
 - Both 32- and 64-bit addressing
 - 256-byte maximum payload size
 - Virtual channel 0 only
 - Traffic class 0 only
 - Full 64-bit decode with 32-bit wide windows
- Pin multiplexing for the high-speed I/O interfaces supports one of the following configurations:
 - 8 PCI Express
 - 4 PCI Express and 4 serial RapidIO
- Power management
 - Supports power saving modes: doze, nap, and sleep
 - Employs dynamic power management, which automatically minimizes power consumption of blocks when they are idle
- System performance monitor
 - Supports eight 32-bit counters that count the occurrence of selected events
 - Ability to count up to 512 counter-specific events
 - Supports 64 reference events that can be counted on any of the eight counters
 - Supports duration and quantity threshold counting
 - Burstiness feature that permits counting of burst events with a programmable time between bursts
 - Triggering and chaining capability
 - Ability to generate an interrupt on overflow
- System access port
 - Uses JTAG interface and a TAP controller to access entire system memory map
 - Supports 32-bit accesses to configuration registers
 - Supports cache-line burst accesses to main memory
 - Supports large block (4-Kbyte) uploads and downloads
 - Supports continuous bit streaming of entire block for fast upload and download
- JTAG boundary scan, designed to comply with IEEE Std. 1149.1™

Table 1. Absolute Maximum Ratings ¹ (continued)

Characteristic	Symbol	Max Value	Unit	Notes
Storage temperature range	T _{STG}	-55 to 150	°C	—

Notes:

- Functional and tested operating conditions are given in Table 2. Absolute maximum ratings are stress ratings only, and functional operation at the maximums is not guaranteed. Stresses beyond those listed may affect device reliability or cause permanent damage to the device.
- The -0.3 to 2.75 V range is for DDR and -0.3 to 1.98 V range is for DDR2.
- The 3.63 V maximum is only supported when the port is configured in GMII, MII, RMII, or TBI modes; otherwise the 2.75 V maximum applies. See Section 8.2, "FIFO, GMII, MII, TBI, RGMII, RMII, and RTBI AC Timing Specifications," for details on the recommended operating conditions per protocol.
- (M,L,O)V_{IN} may overshoot/undershoot to a voltage and for a maximum duration as shown in Figure 2.

2.1.2 Recommended Operating Conditions

The following table provides the recommended operating conditions for this device. Note that the values in this table are the recommended and tested operating conditions. Proper device operation outside these conditions is not guaranteed.

Table 2. Recommended Operating Conditions

Characteristic	Symbol	Recommended Value	Unit	Notes	
Core supply voltage	V _{DD}	1.1 V ± 55 mV	V	—	
PLL supply voltage	AV _{DD}	1.1 V ± 55 mV	V	1	
Core power supply for SerDes transceivers	SV _{DD}	1.1 V ± 55 mV	V	—	
Pad power supply for SerDes transceivers	XV _{DD}	1.1 V ± 55 mV	V	—	
DDR and DDR2 DRAM I/O voltage	GV _{DD}	2.5 V ± 125 mV 1.8 V ± 90 mV	V	—	
Three-speed Ethernet I/O voltage	LV _{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	V	4	
	TV _{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	—	4	
PCI/PCI-X, DUART, system control and power management, I ² C, Ethernet MII management, and JTAG I/O voltage	OV _{DD}	3.3 V ± 165 mV	V	3	
Local bus I/O voltage	BV _{DD}	3.3 V ± 165 mV 2.5 V ± 125 mV	V	—	
Input voltage	DDR and DDR2 DRAM signals	MV _{IN}	GND to GV _{DD}	V	2
	DDR and DDR2 DRAM reference	MV _{REF}	GND to GV _{DD} /2	V	2
	Three-speed Ethernet signals	LV _{IN} TV _{IN}	GND to LV _{DD} GND to TV _{DD}	V	4
	Local bus signals	BV _{IN}	GND to BV _{DD}	V	—
	PCI, DUART, SYSCLK, system control and power management, I ² C, Ethernet MII management, and JTAG signals	OV _{IN}	GND to OV _{DD}	V	3

4.5 Platform to FIFO Restrictions

Note the following FIFO maximum speed restrictions based on platform speed.

For FIFO GMII mode:

$$\text{FIFO TX/RX clock frequency} \leq \text{platform clock frequency}/4.2$$

For example, if the platform frequency is 533 MHz, the FIFO TX/RX clock frequency must be no more than 127 MHz.

For FIFO encoded mode:

$$\text{FIFO TX/RX clock frequency} \leq \text{platform clock frequency}/4.2$$

For example, if the platform frequency is 533 MHz, the FIFO TX/RX clock frequency must be no more than 167 MHz.

4.6 Platform Frequency Requirements for PCI-Express and Serial RapidIO

The CCB clock frequency must be considered for proper operation of the high-speed PCI-Express and Serial RapidIO interfaces as described below.

For proper PCI Express operation, the CCB clock frequency must be greater than:

$$\frac{527 \text{ MHz} \times (\text{PCI-Express link width})}{8}$$

See *MPC8548ERM, Rev. 2, PowerQUICC III Integrated Processor Family Reference Manual*, Section 18.1.3.2, “Link Width,” for PCI Express interface width details.

For proper serial RapidIO operation, the CCB clock frequency must be greater than:

$$\frac{2 \times (0.80) \times (\text{Serial RapidIO interface frequency}) \times (\text{Serial RapidIO link width})}{64}$$

See *MPC8548ERM, Rev. 2, PowerQUICC III Integrated Processor Family Reference Manual*, Section 17.4, “1x/4x LP-Serial Signal Descriptions,” for serial RapidIO interface width and frequency details.

4.7 Other Input Clocks

For information on the input clocks of other functional blocks of the platform see the specific section of this document.

Table 19. DDR SDRAM Output AC Timing Specifications (continued)

At recommended operating conditions.

Parameter	Symbol ¹	Min	Max	Unit	Notes
MDQS epilogue end	t_{DDKHME}	-0.6	0.6	ns	6

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)(reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. Output hold time can be read as DDR timing (DD) from the rising or falling edge of the reference clock (KH or KL) until the output went invalid (AX or DX). For example, t_{DDKHAS} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes from the high (H) state until outputs (A) are setup (S) or output valid time. Also, t_{DDKLDX} symbolizes DDR timing (DD) for the time t_{MCK} memory clock reference (K) goes low (L) until data outputs (D) are invalid (X) or data output hold time.
2. All MCK/MCK referenced measurements are made from the crossing of the two signals ± 0.1 V.
3. ADDR/CMD includes all DDR SDRAM output signals except MCK/MCK, \overline{MCS} , and MDQ/MECC/MDM/MDQS.
4. Note that t_{DDKHMH} follows the symbol conventions described in note 1. For example, t_{DDKHMH} describes the DDR timing (DD) from the rising edge of the MCK[n] clock (KH) until the MDQS signal is valid (MH). t_{DDKHMH} can be modified through control of the MDQS override bits (called WR_DATA_DELAY) in the TIMING_CFG_2 register. This is typically set to the same delay as in DDR_SDRAM_CLK_CNTL[CLK_ADJUST]. The timing parameters listed in the table assume that these 2 parameters have been set to the same adjustment value. See the *MPC8548E PowerQUICC III Integrated Processor Reference Manual* for a description and understanding of the timing modifications enabled by use of these bits.
5. Determined by maximum possible skew between a data strobe (MDQS) and any corresponding bit of data (MDQ), ECC (MECC), or data mask (MDM). The data strobe must be centered inside of the data eye at the pins of the microprocessor.
6. All outputs are referenced to the rising edge of MCK[n] at the pins of the microprocessor. Note that t_{DDKHMP} follows the symbol conventions described in note 1.

NOTE

For the ADDR/CMD setup and hold specifications in [Table 19](#), it is assumed that the clock control register is set to adjust the memory clocks by 1/2 applied cycle.

[Figure 3](#) shows the DDR SDRAM output timing for the MCK to MDQS skew measurement (t_{DDKHMH}).

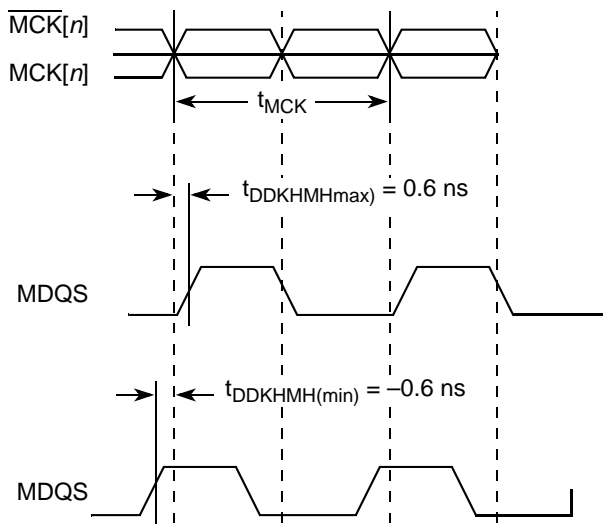


Figure 3. Timing Diagram for t_{DDKHMH}

Table 23. GMII, MII, RMII, TBI, RGMII, RTBI, and FIFO DC Electrical Characteristics

Parameters	Symbol	Min	Max	Unit	Notes
Supply voltage 2.5 V	LV_{DD}/TV_{DD}	2.37	2.63	V	1, 2
Output high voltage ($LV_{DD}/TV_{DD} = \text{Min}$, $I_{OH} = -1.0 \text{ mA}$)	V_{OH}	2.00	$LV_{DD}/TV_{DD} + 0.3$	V	—
Output low voltage ($LV_{DD}/TV_{DD} = \text{Min}$, $I_{OL} = 1.0 \text{ mA}$)	V_{OL}	GND -0.3	0.40	V	—
Input high voltage	V_{IH}	1.70	$LV_{DD}/TV_{DD} + 0.3$	V	—
Input low voltage	V_{IL}	-0.3	0.90	V	—
Input high current ($V_{IN} = LV_{DD}$, $V_{IN} = TV_{DD}$)	I_{IH}	—	10	μA	1, 2, 3
Input low current ($V_{IN} = \text{GND}$)	I_{IL}	-15	—	μA	3

Notes:

1. LV_{DD} supports eTSECs 1 and 2.
2. TV_{DD} supports eTSECs 3 and 4.
3. Note that the symbol V_{IN} , in this case, represents the LV_{IN} and TV_{IN} symbols referenced in [Table 1](#) and [Table 2](#).

8.2 FIFO, GMII, MII, TBI, RGMII, RMII, and RTBI AC Timing Specifications

The AC timing specifications for FIFO, GMII, MII, TBI, RGMII, RMII, and RTBI are presented in this section.

8.2.1 FIFO AC Specifications

The basis for the AC specifications for the eTSEC's FIFO modes is the double data rate RGMII and RTBI specifications, since they have similar performances and are described in a source-synchronous fashion like FIFO modes. However, the FIFO interface provides deliberate skew between the transmitted data and source clock in GMII fashion.

When the eTSEC is configured for FIFO modes, all clocks are supplied from external sources to the relevant eTSEC interface. That is, the transmit clock must be applied to the eTSEC n 's TSEC n _TX_CLK, while the receive clock must be applied to pin TSEC n _RX_CLK. The eTSEC internally uses the transmit clock to synchronously generate transmit data and outputs an echoed copy of the transmit clock back out onto the TSEC n _GTX_CLK pin (while transmit data appears on TSEC n _TXD[7:0], for example). It is intended that external receivers capture eTSEC transmit data using the clock on TSEC n _GTX_CLK as a source-synchronous timing reference. Typically, the clock edge that launched the data can be used, since the clock is delayed by the eTSEC to allow acceptable set-up margin at the receiver. Note that there is relationship between the maximum FIFO speed and the platform speed. For more information see [Section 4.5, "Platform to FIFO Restrictions."](#)

A summary of the FIFO AC specifications appears in [Table 24](#) and [Table 25](#).

Table 24. FIFO Mode Transmit AC Timing Specification

Parameter/Condition	Symbol	Min	Typ	Max	Unit
TX_CLK, GTX_CLK clock period	t_{FIT}	5.3	8.0	100	ns
TX_CLK, GTX_CLK duty cycle	t_{FITH}/t_{FIT}	45	50	55	%
TX_CLK, GTX_CLK peak-to-peak jitter	t_{FITJ}	—	—	250	ps
Rise time TX_CLK (20%–80%)	t_{FITR}	—	—	0.75	ns
Fall time TX_CLK (80%–20%)	t_{FITF}	—	—	0.75	ns
FIFO data TXD[7:0], TX_ER, TX_EN setup time to GTX_CLK	t_{FITDV}	2.0	—	—	ns
GTX_CLK to FIFO data TXD[7:0], TX_ER, TX_EN hold time	t_{FITDX}	0.5	—	3.0	ns

Table 25. FIFO Mode Receive AC Timing Specification

Parameter/Condition	Symbol	Min	Typ	Max	Unit
RX_CLK clock period	t_{FIR}	5.3	8.0	100	ns
RX_CLK duty cycle	t_{FIRH}/t_{FIR}	45	50	55	%
RX_CLK peak-to-peak jitter	t_{FIRJ}	—	—	250	ps
Rise time RX_CLK (20%–80%)	t_{FIRR}	—	—	0.75	ns
Fall time RX_CLK (80%–20%)	t_{FIRF}	—	—	0.75	ns
RXD[7:0], RX_DV, RX_ER setup time to RX_CLK	t_{FIRDV}	1.5	—	—	ns
RXD[7:0], RX_DV, RX_ER hold time to RX_CLK	t_{FIRDX}	0.5	—	—	ns

Note:

1. The minimum cycle period of the TX_CLK and RX_CLK is dependent on the maximum platform frequency of the speed bins the part belongs to as well as the FIFO mode under operation. See [Section 4.5, “Platform to FIFO Restrictions.”](#)

Timing diagrams for FIFO appear in [Figure 6](#) and [Figure 7](#).

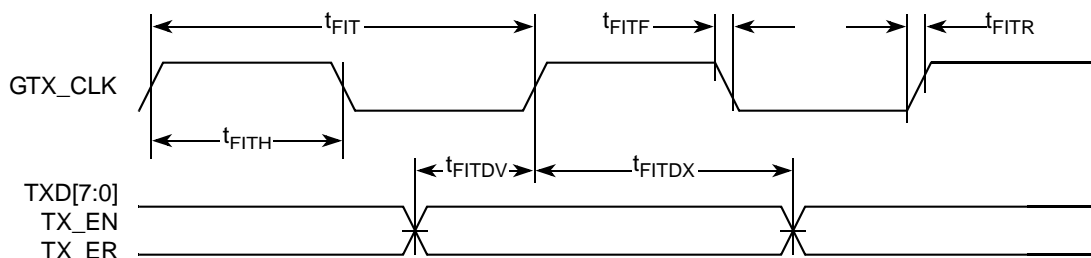


Figure 6. FIFO Transmit AC Timing Diagram

Figure 8 shows the GMII transmit AC timing diagram.

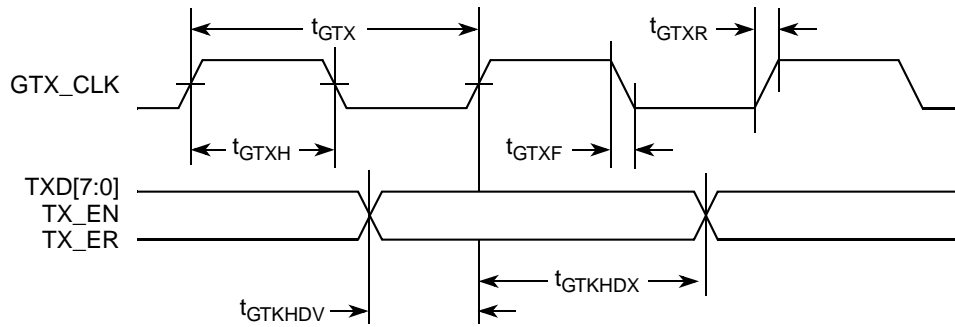


Figure 8. GMII Transmit AC Timing Diagram

8.2.2.2 GMII Receive AC Timing Specifications

This table provides the GMII receive AC timing specifications.

Table 27. GMII Receive AC Timing Specifications

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
RX_CLK clock period	t_{GRX}	—	8.0	—	ns
RX_CLK duty cycle	t_{GRXH}/t_{GRX}	35	—	75	ns
RXD[7:0], RX_DV, RX_ER setup time to RX_CLK	t_{GRDVKH}	2.0	—	—	ns
RXD[7:0], RX_DV, RX_ER hold time to RX_CLK	t_{GRDXKH}	0	—	—	ns
RX_CLK clock rise (20%-80%)	t_{GRXR}^2	—	—	1.0	ns
RX_CLK clock fall time (80%-20%)	t_{GRXF}^2	—	—	1.0	ns

Notes:

- The symbols used for timing specifications follow the pattern of $t_{(\text{first two letters of functional block})(\text{signal})(\text{state})(\text{reference})(\text{state})}$ for inputs and $t_{(\text{first two letters of functional block})(\text{reference})(\text{state})(\text{signal})(\text{state})}$ for outputs. For example, t_{GRDVKH} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{RX} clock reference (K) going to the high state (H) or setup time. Also, t_{GRDXKL} symbolizes GMII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{GRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{GRX} represents the GMII (G) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
- Guaranteed by design.

Figure 9 provides the AC test load for eTSEC.

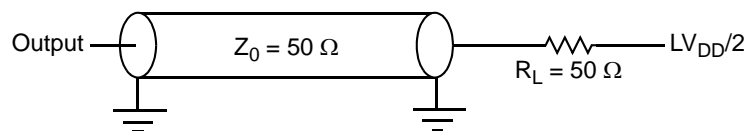


Figure 9. eTSEC AC Test Load

Table 34. RMIIT Transmit AC Timing Specifications (continued)

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
TSEC _n _TX_CLK to RMIIT data TXD[1:0], TX_EN delay	t _{RMTDX}	1.0	—	10.0	ns

Note:

1. The symbols used for timing specifications follow the pattern of t_{(first two letters of functional block)(signal)(state)(reference)(state)} for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{MTKHDX} symbolizes MII transmit timing (MT) for the time t_{MTX} clock reference (K) going high (H) until data outputs (D) are invalid (X). Note that, in general, the clock reference symbol representation is based on two to three letters representing the clock of a particular functional. For example, the subscript of t_{MTX} represents the MII(M) transmit (TX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Figure 18 shows the RMIIT transmit AC timing diagram.

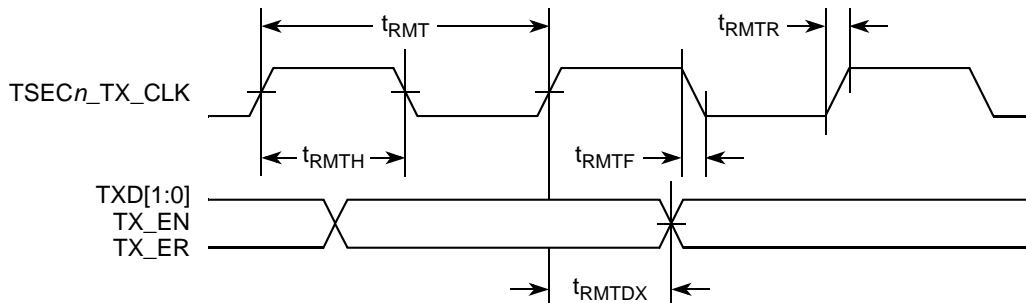


Figure 18. RMIIT Transmit AC Timing Diagram

8.2.7.2 RMIIT Receive AC Timing Specifications

Table 35. RMIIT Receive AC Timing Specifications

Parameter/Condition	Symbol ¹	Min	Typ	Max	Unit
TSEC _n _TX_CLK clock period	t _{RMR}	15.0	20.0	25.0	ns
TSEC _n _TX_CLK duty cycle	t _{RMRH}	35	50	65	%
TSEC _n _TX_CLK peak-to-peak jitter	t _{RMRJ}	—	—	250	ps
Rise time TSEC _n _TX_CLK(20%–80%)	t _{RMRR}	1.0	—	2.0	ns
Fall time TSEC _n _TX_CLK (80%–20%)	t _{RMRF}	1.0	—	2.0	ns
RXD[1:0], CRS_DV, RX_ER setup time to REF_CLK rising edge	t _{RMRDV}	4.0	—	—	ns
RXD[1:0], CRS_DV, RX_ER hold time to REF_CLK rising edge	t _{RMRDx}	2.0	—	—	ns

Note:

1. The symbols used for timing specifications follow the pattern of t_{(first two letters of functional block)(signal)(state)(reference)(state)} for inputs and t_{(first two letters of functional block)(reference)(state)(signal)(state)} for outputs. For example, t_{MRDVKH} symbolizes MII receive timing (MR) with respect to the time data input signals (D) reach the valid state (V) relative to the t_{MRX} clock reference (K) going to the high (H) state or setup time. Also, t_{MRDXKL} symbolizes MII receive timing (GR) with respect to the time data input signals (D) went invalid (X) relative to the t_{MRX} clock reference (K) going to the low (L) state or hold time. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For example, the subscript of t_{MRX} represents the MII (M) receive (RX) clock. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).

Table 42. Local Bus Timing Parameters—PLL Bypassed (continued)

Parameter	Symbol ¹	Min	Max	Unit	Notes
$\overline{\text{LGTA}}/\text{LUPWAIT}$ input hold from local bus clock	t_{LBIXKL2}	-1.3	—	ns	4, 5
LALE output transition to LAD/LDP output transition (LATCH hold time)	t_{LBOTOT}	1.5	—	ns	6
Local bus clock to output valid (except LAD/LDP and LALE)	t_{LBKLOV1}	—	-0.3	ns	—
Local bus clock to data valid for LAD/LDP	t_{LBKLOV2}	—	-0.1	ns	4
Local bus clock to address valid for LAD	t_{LBKLOV3}	—	0	ns	4
Local bus clock to LALE assertion	t_{LBKLOV4}	—	0	ns	4
Output hold from local bus clock (except LAD/LDP and LALE)	t_{LBKLOX1}	-3.7	—	ns	4
Output hold from local bus clock for LAD/LDP	t_{LBKLOX2}	-3.7	—	ns	4
Local bus clock to output high Impedance (except LAD/LDP and LALE)	t_{LBKLOZ1}	—	0.2	ns	7
Local bus clock to output high impedance for LAD/LDP	t_{LBKLOZ2}	—	0.2	ns	7

Notes:

1. The symbols used for timing specifications follow the pattern of $t_{\text{(first two letters of functional block)(signal)(state)(reference)(state)}}$ for inputs and $t_{\text{(first two letters of functional block)(reference)(state)(signal)(state)}}$ for outputs. For example, t_{LBIXKH1} symbolizes local bus timing (LB) for the input (I) to go invalid (X) with respect to the time the t_{LBK} clock reference (K) goes high (H), in this case for clock one (1). Also, t_{LBKHOX} symbolizes local bus timing (LB) for the t_{LBK} clock reference (K) to go high (H), with respect to the output (O) going invalid (X) or output hold time.
2. All timings are in reference to local bus clock for PLL bypass mode. Timings may be negative with respect to the local bus clock because the actual launch and capture of signals is done with the internal launch/capture clock, which precedes LCLK by t_{LBKHKT} .
3. Maximum possible clock skew between a clock LCLK[m] and a relative clock LCLK[n]. Skew measured between complementary signals at $BV_{\text{DD}}/2$.
4. All signals are measured from $BV_{\text{DD}}/2$ of the rising edge of local bus clock for PLL bypass mode to $0.4 \times BV_{\text{DD}}$ of the signal in question for 3.3-V signaling levels.
5. Input timings are measured at the pin.
6. The value of t_{LBOTOT} is the measurement of the minimum time between the negation of LALE and any change in LAD.
7. For purposes of active/float timing measurements, the Hi-Z or off state is defined to be when the total current delivered through the component pin is less than or equal to the leakage current specification.
8. Guaranteed by characterization.
9. Guaranteed by design.

Table 44. JTAG AC Timing Specifications (Independent of SYSCLK)¹ (continued)

Parameter	Symbol ²	Min	Max	Unit	Notes
Valid times: Boundary-scan data TDO	t_{JTKLDV} t_{JTKLOV}	4 2	20 10	ns	5
Output hold times: Boundary-scan data TDO	t_{JTKLDX} t_{JTKLOX}	30 30	— —	ns	5
JTAG external clock to output high impedance: Boundary-scan data TDO	t_{JTKLDZ} t_{JTKLOZ}	3 3	19 9	ns	5, 6

Notes:

1. All outputs are measured from the midpoint voltage of the falling/rising edge of t_{TCLK} to the midpoint of the signal in question. The output timings are measured at the pins. All output timings assume a purely resistive 50-Ω load (see Figure 29). Time-of-flight delays must be added for trace lengths, vias, and connectors in the system.
2. The symbols used for timing specifications follow the pattern of $t_{(first\ two\ letters\ of\ functional\ block)(signal)(state)(reference)(state)}$ for inputs and $t_{(first\ two\ letters\ of\ functional\ block)(reference)(state)(signal)(state)}$ for outputs. For example, t_{JTDVXH} symbolizes JTAG device timing (JT) with respect to the time data input signals (D) reaching the valid state (V) relative to the t_{JTG} clock reference (K) going to the high (H) state or setup time. Also, t_{JTDXKH} symbolizes JTAG timing (JT) with respect to the time data input signals (D) went invalid (X) relative to the t_{JTG} clock reference (K) going to the high (H) state. Note that, in general, the clock reference symbol representation is based on three letters representing the clock of a particular functional. For rise and fall times, the latter convention is used with the appropriate letter: R (rise) or F (fall).
3. \overline{TRST} is an asynchronous level sensitive signal. The setup time is for test purposes only.
4. Non-JTAG signal input timing with respect to t_{TCLK} .
5. Non-JTAG signal output timing with respect to t_{TCLK} .
6. Guaranteed by design.

Figure 29 provides the AC test load for TDO and the boundary-scan outputs.

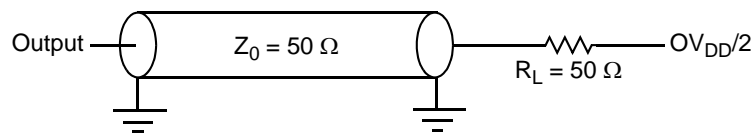


Figure 29. AC Test Load for the JTAG Interface

Figure 30 provides the JTAG clock input timing diagram.

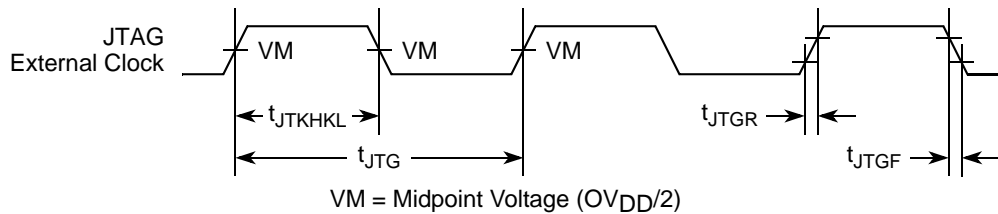


Figure 30. JTAG Clock Input Timing Diagram

The eye diagram must be valid for any 250 consecutive UIs.

A recovered TX UI is calculated over 3500 consecutive unit intervals of sample data. The eye diagram is created using all edges of the 250 consecutive UI in the center of the 3500 UI used for calculating the TX UI.

NOTE

The reference impedance for return loss measurements is 50. to ground for both the D+ and D- line (that is, as measured by a vector network analyzer with 50-Ω probes—see Figure 50). Note that the series capacitors, CTX, are optional for the return loss measurement.

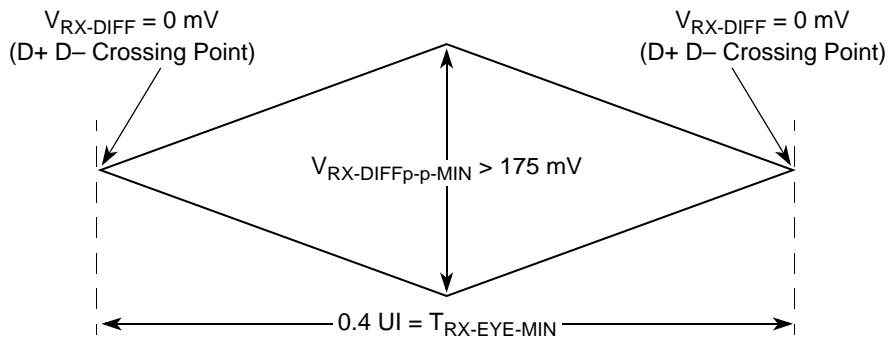


Figure 49. Minimum Receiver Eye Timing and Voltage Compliance Specification

17.5.1 Compliance Test and Measurement Load

The AC timing and voltage parameters must be verified at the measurement point, as specified within 0.2 inches of the package pins, into a test/measurement load shown in Figure 50.

NOTE

The allowance of the measurement point to be within 0.2 inches of the package pins is meant to acknowledge that package/board routing may benefit from D+ and D- not being exactly matched in length at the package pin boundary.

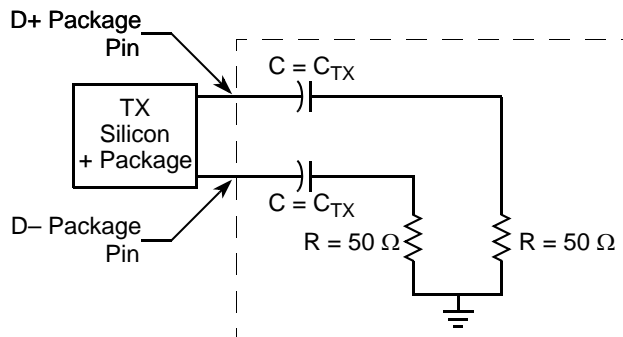


Figure 50. Compliance Test/Measurement Load

18.5 Explanatory Note on Transmitter and Receiver Specifications

AC electrical specifications are given for transmitter and receiver. Long- and short-run interfaces at three baud rates (a total of six cases) are described.

The parameters for the AC electrical specifications are guided by the XAUI electrical interface specified in Clause 47 of IEEE 802.3ae-2002.

XAUI has similar application goals to Serial RapidIO, as described in Section 8.1. The goal of this standard is that electrical designs for Serial RapidIO can reuse electrical designs for XAUI, suitably modified for applications at the baud intervals and reaches described herein.

18.6 Transmitter Specifications

LP-serial transmitter electrical and timing specifications are stated in the text and tables of this section.

The differential return loss, S_{11} , of the transmitter in each case shall be better than:

- -10 dB for $(\text{baud frequency})/10 < \text{Freq}(f) < 625$ MHz, and
- -10 dB + $10\log(f/625 \text{ MHz})$ dB for $625 \text{ MHz} \leq \text{Freq}(f) \leq \text{baud frequency}$

The reference impedance for the differential return loss measurements is $100\text{-}\Omega$ resistive. Differential return loss includes contributions from on-chip circuitry, chip packaging, and any off-chip components related to the driver. The output impedance requirement applies to all valid output levels.

It is recommended that the 20%–80% rise/fall time of the transmitter, as measured at the transmitter output, in each case have a minimum value 60 ps.

It is recommended that the timing skew at the output of an LP-serial transmitter between the two signals that comprise a differential pair not exceed 25 ps at 1.25 GB, 20 ps at 2.50 GB, and 15 ps at 3.125 GB.

Table 59. Short Run Transmitter AC Timing Specifications—1.25 GBaud

Characteristic	Symbol	Range		Unit	Notes
		Min	Max		
Output voltage	V_O	-0.40	2.30	V	Voltage relative to COMMON of either signal comprising a differential pair
Differential output voltage	V_{DIFFPP}	500	1000	mV p-p	—
Deterministic jitter	J_D	—	0.17	UI p-p	—
Total jitter	J_T	—	0.35	UI p-p	—
Multiple output skew	S_{MO}	—	1000	ps	Skew at the transmitter output between lanes of a multilane link
Unit Interval	UI	800	800	ps	± 100 ppm

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{PCI1_REQ}}[4:1]$	AH2, AG4, AG3, AH4	I	OV_{DD}	— — — — —
$\overline{\text{PCI1_REQ0}}$	AH3	I/O	OV_{DD}	—
$\overline{\text{PCI1_CLK}}$	AH26	I	OV_{DD}	39
$\overline{\text{PCI1_DEVSEL}}$	AH11	I/O	OV_{DD}	2
$\overline{\text{PCI1_FRAME}}$	AE11	I/O	OV_{DD}	2
$\overline{\text{PCI1_IDSEL}}$	AG9	I	OV_{DD}	—
$\overline{\text{PCI1_REQ64/PCI2_FRAME}}$	AF14	I/O	OV_{DD}	2, 5, 10
$\overline{\text{PCI1_ACK64/PCI2_DEVSEL}}$	V15	I/O	OV_{DD}	2
$\overline{\text{PCI2_CLK}}$	AE28	I	OV_{DD}	39
$\overline{\text{PCI2_IRDY}}$	AD26	I/O	OV_{DD}	2
$\overline{\text{PCI2_PERR}}$	AD25	I/O	OV_{DD}	2
$\overline{\text{PCI2_GNT}}[4:1]$	AE26, AG24, AF25, AE25	O	OV_{DD}	5, 9, 35
$\overline{\text{PCI2_GNT0}}$	AG25	I/O	OV_{DD}	—
$\overline{\text{PCI2_SERR}}$	AD24	I/O	OV_{DD}	2, 4
$\overline{\text{PCI2_STOP}}$	AF24	I/O	OV_{DD}	2
$\overline{\text{PCI2_TRDY}}$	AD27	I/O	OV_{DD}	2
$\overline{\text{PCI2_REQ}}[4:1]$	AD28, AE27, W17, AF26	I	OV_{DD}	—
$\overline{\text{PCI2_REQ0}}$	AH25	I/O	OV_{DD}	—
DDR SDRAM Memory Interface				
MDQ[0:63]	L18, J18, K14, L13, L19, M18, L15, L14, A17, B17, A13, B12, C18, B18, B13, A12, H18, F18, J14, F15, K19, J19, H16, K15, D17, G16, K13, D14, D18, F17, F14, E14, A7, A6, D5, A4, C8, D7, B5, B4, A2, B1, D1, E4, A3, B2, D2, E3, F3, G4, J5, K5, F6, G5, J6, K4, J1, K2, M5, M3, J3, J2, L1, M6	I/O	GV_{DD}	—
MECC[0:7]	H13, F13, F11, C11, J13, G13, D12, M12	I/O	GV_{DD}	—
MDM[0:8]	M17, C16, K17, E16, B6, C4, H4, K1, E13	O	GV_{DD}	—
MDQS[0:8]	M15, A16, G17, G14, A5, D3, H1, L2, C13	I/O	GV_{DD}	—
$\overline{\text{MDQS}}[0:8]$	L17, B16, J16, H14, C6, C2, H3, L4, D13	I/O	GV_{DD}	—
MA[0:15]	A8, F9, D9, B9, A9, L10, M10, H10, K10, G10, B8, E10, B10, G6, A10, L11	O	GV_{DD}	—
MBA[0:2]	F7, J7, M11	O	GV_{DD}	—

Table 71. MPC8548E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
SENSEVSS	M16	—	—	13
Analog Signals				
MVREF	A18	I Reference voltage signal for DDR	MVREF	—
SD_IMP_CAL_RX	L28	I	200Ω to GND	—
SD_IMP_CAL_TX	AB26	I	100Ω to GND	—
SD_PLL_TPA	U26	O	—	24

Notes:

1. All multiplexed signals are listed only once and do not re-occur. For example, $\overline{\text{LCS5/DMA_REQ2}}$ is listed only once in the local bus controller section, and is not mentioned in the DMA section even though the pin also functions as DMA_REQ2 .
2. Recommend a weak pull-up resistor (2–10 kΩ) be placed on this pin to OV_{DD} .
3. A valid clock must be provided at POR if $\text{TSEC4_TXD}[2]$ is set = 1.
4. This pin is an open drain signal.
5. This pin is a reset configuration pin. It has a weak internal pull-up P-FET which is enabled only when the processor is in the reset state. This pull-up is designed such that it can be overpowered by an external 4.7-kΩ pull-down resistor. However, if the signal is intended to be high after reset, and if there is any device on the net which might pull down the value of the net at reset, then a pullup or active driver is needed.
6. Treat these pins as no connects (NC) unless using debug address functionality.
7. The value of $\text{LA}[28:31]$ during reset sets the CCB clock to SYSCLK PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See [Section 20.2, "CCB/SYSCLK PLL Ratio."](#)
8. The value of LALE , LGPL2 , and LBCTL at reset set the e500 core clock to CCB clock PLL ratio. These pins require 4.7-kΩ pull-up or pull-down resistors. See the [Section 20.3, "e500 Core PLL Ratio."](#)
9. Functionally, this pin is an output, but structurally it is an I/O because it either samples configuration input during reset or because it has other manufacturing test functions. This pin therefore is described as an I/O for boundary scan.
10. This pin functionally requires a pull-up resistor, but during reset it is a configuration input that controls 32- vs. 64-bit PCI operation. Therefore, it must be actively driven low during reset by reset logic if the device is to be configured to be a 64-bit PCI device. See the *PCI Specification*.
11. This output is actively driven during reset rather than being three-stated during reset.
12. These JTAG pins have weak internal pull-up P-FETs that are always enabled.
13. These pins are connected to the $\text{V}_{\text{DD}}/\text{GND}$ planes internally and may be used by the core power supply to improve tracking and regulation.
14. Internal thermally sensitive resistor.
15. No connections must be made to these pins if they are not used.
16. These pins are not connected for any use.
17. PCI specifications recommend that a weak pull-up resistor (2–10 kΩ) be placed on the higher order pins to OV_{DD} when using 64-bit buffer mode (pins $\text{PCI_AD}[63:32]$ and $\text{PCI1_C_BE}[7:4]$).
19. If this pin is connected to a device that pulls down during reset, an external pull-up is required to drive this pin to a safe state during reset.
20. This pin is only an output in FIFO mode when used as Rx flow control.
24. Do not connect.

Table 73. MPC8545E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
$\overline{\text{UDE}}$	AH16	I	OV_{DD}	—
$\overline{\text{MCP}}$	AG19	I	OV_{DD}	—
IRQ[0:7]	AG23, AF18, AE18, AF20, AG18, AF17, AH24, AE20	I	OV_{DD}	—
IRQ[8]	AF19	I	OV_{DD}	—
IRQ[9]/ $\overline{\text{DMA_DREQ3}}$	AF21	I	OV_{DD}	1
IRQ[10]/ $\overline{\text{DMA_DACK3}}$	AE19	I/O	OV_{DD}	1
IRQ[11]/ $\overline{\text{DMA_DDONE3}}$	AD20	I/O	OV_{DD}	1
$\overline{\text{IRQ_OUT}}$	AD18	O	OV_{DD}	2, 4
Ethernet Management Interface				
EC_MDC	AB9	O	OV_{DD}	5, 9
EC_MDIO	AC8	I/O	OV_{DD}	—
Gigabit Reference Clock				
EC_GTX_CLK125	V11	I	LV_{DD}	—
Three-Speed Ethernet Controller (Gigabit Ethernet 1)				
TSEC1_RXD[7:0]	R5, U1, R3, U2, V3, V1, T3, T2	I	LV_{DD}	—
TSEC1_TXD[7:0]	T10, V7, U10, U5, U4, V6, T5, T8	O	LV_{DD}	5, 9
TSEC1_COL	R4	I	LV_{DD}	—
TSEC1_CRS	V5	I/O	LV_{DD}	20
TSEC1_GTX_CLK	U7	O	LV_{DD}	—
TSEC1_RX_CLK	U3	I	LV_{DD}	—
TSEC1_RX_DV	V2	I	LV_{DD}	—
TSEC1_RX_ER	T1	I	LV_{DD}	—
TSEC1_TX_CLK	T6	I	LV_{DD}	—
TSEC1_TX_EN	U9	O	LV_{DD}	30
TSEC1_TX_ER	T7	O	LV_{DD}	—
GPIN[0:7]	P2, R2, N1, N2, P3, M2, M1, N3	I	LV_{DD}	103
GPOUT[0:5]	N9, N10, P8, N7, R9, N5	O	LV_{DD}	—
cfg_dram_type0/GPOUT6	R8	O	LV_{DD}	5, 9
GPOUT7	N6	O	LV_{DD}	—
Reserved	P1	—	—	104
Reserved	R6	—	—	104
Reserved	P6	—	—	15
Reserved	N4	—	—	105

Table 73. MPC8545E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
FIFO1_RXC2	P5	I	LV _{DD}	104
Reserved	R1	—	—	104
Reserved	P10	—	—	105
FIFO1_TXC2	P7	O	LV _{DD}	15
cfg_dram_type1	R10	I	LV _{DD}	5
Three-Speed Ethernet Controller (Gigabit Ethernet 3)				
TSEC3_TXD[3:0]	V8, W10, Y10, W7	O	TV _{DD}	5, 9, 29
TSEC3_RXD[3:0]	Y1, W3, W5, W4	I	TV _{DD}	—
TSEC3_GTX_CLK	W8	O	TV _{DD}	—
TSEC3_RX_CLK	W2	I	TV _{DD}	—
TSEC3_RX_DV	W1	I	TV _{DD}	—
TSEC3_RX_ER	Y2	I	TV _{DD}	—
TSEC3_TX_CLK	V10	I	TV _{DD}	—
TSEC3_TX_EN	V9	O	TV _{DD}	30
TSEC3_TXD[7:4]	AB8, Y7, AA7, Y8	O	TV _{DD}	5, 9, 29
TSEC3_RXD[7:4]	AA1, Y3, AA2, AA4	I	TV _{DD}	—
Reserved	AA5	—	—	15
TSEC3_COL	Y5	I	TV _{DD}	—
TSEC3_CRS	AA3	I/O	TV _{DD}	31
TSEC3_TX_ER	AB6	O	TV _{DD}	—
DUART				
$\overline{\text{UART_CTS}}$ [0:1]	AB3, AC5	I	OV _{DD}	—
$\overline{\text{UART_RTS}}$ [0:1]	AC6, AD7	O	OV _{DD}	—
UART_SIN[0:1]	AB5, AC7	I	OV _{DD}	—
UART_SOUT[0:1]	AB7, AD8	O	OV _{DD}	—
I²C interface				
IIC1_SCL	AG22	I/O	OV _{DD}	4, 27
IIC1_SDA	AG21	I/O	OV _{DD}	4, 27
IIC2_SCL	AG15	I/O	OV _{DD}	4, 27
IIC2_SDA	AG14	I/O	OV _{DD}	4, 27
SerDes				
SD_RX[0:3]	M28, N26, P28, R26	I	XV _{DD}	—
$\overline{\text{SD_RX}}$ [0:3]	M27, N25, P27, R25	I	XV _{DD}	—
SD_TX[0:3]	M22, N20, P22, R20	O	XV _{DD}	—

Table 74. MPC8543E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
\overline{MWE}	E7	O	GV _{DD}	—
\overline{MCAS}	H7	O	GV _{DD}	—
\overline{MRAS}	L8	O	GV _{DD}	—
MCKE[0:3]	F10, C10, J11, H11	O	GV _{DD}	11
\overline{MCS} [0:3]	K8, J8, G8, F8	O	GV _{DD}	—
MCK[0:5]	H9, B15, G2, M9, A14, F1	O	GV _{DD}	—
\overline{MCK} [0:5]	J9, A15, G1, L9, B14, F2	O	GV _{DD}	—
MODT[0:3]	E6, K6, L7, M7	O	GV _{DD}	—
MDIC[0:1]	A19, B19	I/O	GV _{DD}	36
Local Bus Controller Interface				
LAD[0:31]	E27, B20, H19, F25, A20, C19, E28, J23, A25, K22, B28, D27, D19, J22, K20, D28, D25, B25, E22, F22, F21, C25, C22, B23, F20, A23, A22, E19, A21, D21, F19, B21	I/O	BV _{DD}	—
LDP[0:3]	K21, C28, B26, B22	I/O	BV _{DD}	—
LA[27]	H21	O	BV _{DD}	5, 9
LA[28:31]	H20, A27, D26, A28	O	BV _{DD}	5, 7, 9
\overline{LCS} [0:4]	J25, C20, J24, G26, A26	O	BV _{DD}	—
$\overline{LCS5/DMA_DREQ2}$	D23	I/O	BV _{DD}	1
$\overline{LCS6/DMA_DACK2}$	G20	O	BV _{DD}	1
$\overline{LCS7/DMA_DDONE2}$	E21	O	BV _{DD}	1
$\overline{LWE0/LBS0/LSDDQM}[0]$	G25	O	BV _{DD}	5, 9
$\overline{LWE1/LBS1/LSDDQM}[1]$	C23	O	BV _{DD}	5, 9
$\overline{LWE2/LBS2/LSDDQM}[2]$	J21	O	BV _{DD}	5, 9
$\overline{LWE3/LBS3/LSDDQM}[3]$	A24	O	BV _{DD}	5, 9
LALE	H24	O	BV _{DD}	5, 8, 9
LBCTL	G27	O	BV _{DD}	5, 8, 9
LGPL0/LSDA10	F23	O	BV _{DD}	5, 9
LGPL1/ \overline{LSDWE}	G22	O	BV _{DD}	5, 9
LGPL2/ $\overline{LOE/LSDRAS}$	B27	O	BV _{DD}	5, 8, 9
LGPL3/ \overline{LSDCAS}	F24	O	BV _{DD}	5, 9
LGPL4/LGTA/LUPWAIT/LPBSE	H23	I/O	BV _{DD}	—
LGPL5	E26	O	BV _{DD}	5, 9
LCKE	E24	O	BV _{DD}	—
LCLK[0:2]	E23, D24, H22	O	BV _{DD}	—

Table 74. MPC8543E Pinout Listing (continued)

Signal	Package Pin Number	Pin Type	Power Supply	Notes
TV _{DD}	W9, Y6	Power for TSEC3 and TSEC4 (2.5 V, 3.3 V)	TV _{DD}	—
GV _{DD}	B3, B11, C7, C9, C14, C17, D4, D6, D10, D15, E2, E8, E11, E18, F5, F12, F16, G3, G7, G9, G11, H5, H12, H15, H17, J10, K3, K12, K16, K18, L6, M4, M8, M13	Power for DDR1 and DDR2 DRAM I/O voltage (1.8 V, 2.5 V)	GV _{DD}	—
BV _{DD}	C21, C24, C27, E20, E25, G19, G23, H26, J20	Power for local bus (1.8 V, 2.5 V, 3.3 V)	BV _{DD}	—
V _{DD}	M19, N12, N14, N16, N18, P11, P13, P15, P17, P19, R12, R14, R16, R18, T11, T13, T15, T17, T19, U12, U14, U16, U18, V17, V19	Power for core (1.1 V)	V _{DD}	—
SV _{DD}	L25, L27, M24, N28, P24, P26, R24, R27, T25, V24, V26, W24, W27, Y25, AA28, AC27	Core power for SerDes transceivers (1.1 V)	SV _{DD}	—
XV _{DD}	L20, L22, N23, P21, R22, T20, U23, V21, W22, Y20	Pad power for SerDes transceivers (1.1 V)	XV _{DD}	—
AVDD_LBIU	J28	Power for local bus PLL (1.1 V)	—	26
AVDD_PCI1	AH21	Power for PCI1 PLL (1.1 V)	—	26
AVDD_PCI2	AH22	Power for PCI2 PLL (1.1 V)	—	26
AVDD_CORE	AH15	Power for e500 PLL (1.1 V)	—	26
AVDD_PLAT	AH19	Power for CCB PLL (1.1 V)	—	26
AVDD_SRDS	U25	Power for SRDSPLL (1.1 V)	—	26
SENSEVDD	M14	O	V _{DD}	13

- First, the board must have at least 10×10 -nF SMT ceramic chip capacitors as close as possible to the supply balls of the device. Where the board has blind vias, these capacitors must be placed directly below the chip supply and ground connections. Where the board does not have blind vias, these capacitors must be placed in a ring around the device as close to the supply and ground connections as possible.
- Second, there must be a 1- μ F ceramic chip capacitor from each SerDes supply (SV_{DD} and XV_{DD}) to the board ground plane on each side of the device. This must be done for all SerDes supplies.
- Third, between the device and any SerDes voltage regulator there must be a 10- μ F, low equivalent series resistance (ESR) SMT tantalum chip capacitor and a 100- μ F, low ESR SMT tantalum chip capacitor. This must be done for all SerDes supplies.

22.5 Connection Recommendations

To ensure reliable operation, it is highly recommended to connect unused inputs to an appropriate signal level. All unused active low inputs must be tied to V_{DD} , TV_{DD} , BV_{DD} , OV_{DD} , GV_{DD} , and LV_{DD} , as required. All unused active high inputs must be connected to GND. All NC (no-connect) signals must remain unconnected. Power and ground connections must be made to all external V_{DD} , TV_{DD} , BV_{DD} , OV_{DD} , GV_{DD} , LV_{DD} , and GND pins of the device.

22.6 Pull-Up and Pull-Down Resistor Requirements

The device requires weak pull-up resistors (2–10 k Ω is recommended) on open drain type pins including I²C pins and PIC (interrupt) pins.

Correct operation of the JTAG interface requires configuration of a group of system control pins as demonstrated in Figure 63. Care must be taken to ensure that these pins are maintained at a valid deasserted state under normal operating conditions as most have asynchronous behavior and spurious assertion gives unpredictable results.

The following pins must not be pulled down during power-on reset: $TSEC3_TXD[3]$, $\overline{HRESET_REQ}$, $TRIG_OUT/READY/QUIESCENCE$, $MSRCID[2:4]$, ASLEEP. The $\overline{DMA_DACK}[0:1]$, and $TEST_SEL/TEST_SEL$ pins must be set to a proper state during POR configuration. See the pinlist table of the individual device for more details

See the PCI 2.2 specification for all pull ups required for PCI.

22.7 Output Buffer DC Impedance

The device drivers are characterized over process, voltage, and temperature. For all buses, the driver is a push-pull single-ended driver type (open drain for I²C).

To measure Z_0 for the single-ended drivers, an external resistor is connected from the chip pad to OV_{DD} or GND. Then, the value of each resistor is varied until the pad voltage is $OV_{DD}/2$ (see Figure 61). The output impedance is the average of two components, the resistances of the pull-up and pull-down devices. When data is held high, SW1 is closed (SW2 is open) and R_P is trimmed until the voltage at the pad equals $OV_{DD}/2$. R_P then becomes the resistance of the pull-up devices. R_P and R_N are designed to be close to each other in value. Then, $Z_0 = (R_P + R_N)/2$.

24 Document Revision History

The following table provides a revision history for this hardware specification.

Table 88. Document Revision History

Rev. Number	Date	Substantive Change(s)
9	02/2012	<ul style="list-style-type: none"> Updated Section 21.2, "Thermal for Version 2.1.1, 2.1.2, and 2.1.3 Silicon FC-PBGA with Full Lid and Version 3.1.x Silicon with Stamped Lid," with version 3.0 silicon information. Added Figure 56, "Mechanical Dimensions and Bottom Surface Nomenclature of the FC-PBGA with Stamped Lid." Updated Table 87, "Part Numbering Nomenclature," with version 3.0 silicon information. Removed Note from Section 5.1, "Power-On Ramp Rate". Changed the Table 10 title to "Power Supply Ramp Rate". Removed table 11. Updated the title of Section 21.2, "Thermal for Version 2.1.1, 2.1.2, and 2.1.3 Silicon FC-PBGA with Full Lid and Version 3.1.x Silicon with Stamped Lid" to include Thermal Version 2.1.3 and Version 3.1.x Silicon. Corrected the leaded Solder Ball composition in Table 70, "Package Parameters" Updated Table 87, "Part Numbering Nomenclature," with Version 3.1.x silicon information. Updated the Min and Max value of TDO in the valid times row of Table 44, "JTAG AC Timing Specifications (Independent of SYSCLK)"¹ from 4 and 25 to 2 and 10 respectively .
8	04/2011	<ul style="list-style-type: none"> Added Section 14.1, "GPOUT/GPIN Electrical Characteristics." Updated Table 71, "MPC8548E Pinout Listing," Table 72, "MPC8547E Pinout Listing," Table 73, "MPC8545E Pinout Listing," and Table 74, "MPC8543E Pinout Listing," to reflect that the TDO signal is not driven during HRSET* assertion. Updated Table 87, "Part Numbering Nomenclature" with Ver. 2.1.3 silicon information.
7	09/2010	<ul style="list-style-type: none"> In Table 37, "MII Management AC Timing Specifications, modified the fifth row from "MDC to MDIO delay tMDKHDX (16 × tptb_clk × 8) – 3 — (16 × tptb_clk × 8) + 3" to "MDC to MDIO delay tMDKHDX (16 × tCCB × 8) – 3 — (16 × tCCB × 8) + 3." Updated Figure 55, "Mechanical Dimensions and Bottom Surface Nomenclature of the HiCTE FC-CBGA and FC-PBGA with Full Lid and figure notes.
6	12/2009	<ul style="list-style-type: none"> In Section 5.1, "Power-On Ramp Rate" added explanation that Power-On Ramp Rate is required to avoid falsely triggering ESD circuitry. In Table 13 changed required ramp rate from 545 V/s for MVREF and VDD/XVDD/SVDD to 3500 V/s for MVREF and 4000 V/s for VDD. In Table 13 deleted ramp rate requirement for XVDD/SVDD. In Table 13 footnote 1 changed voltage range of concern from 0–400 mV to 20–500mV. In Table 13 added footnote 2 explaining that VDD voltage ramp rate is intended to control ramp rate of AVDD pins.
5	10/2009	<ul style="list-style-type: none"> In Table 27, "GMII Receive AC Timing Specifications," changed duty cycle specification from 40/60 to 35/75 for RX_CLK duty cycle. Updated tMDKHDX in Table 37, "MII Management AC Timing Specifications." Added a reference to Revision 2.1.2. Updated Table 55, "MII Management AC Timing Specifications." Added Section 5.1, "Power-On Ramp Rate."